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Data Sheet

August 15, 2026

BURLEIGH

Burleigh WA-20 Wavemeter

Burleigh WA-20 Optical Wavelength Meter 0.4 to 4 um The Burleigh WA-20 wavemeter measures absolute wavelength of CW lasers from 0.4 to 4 um with automatic operation. OEM-quoted WA-20 specifications list vacuum wavelength readout from 0.4 to 1.0 um, accuracy to plus or minus 1 part in 10^6 , 1.6 s display update, and high/low resolution readout modes. CW laser tuning and drift monitoring where grating spectrometers are slower or less absolute. Fully automatic wavelength measurement without external reference The Burleigh WA-20 wavemeter measures absolute wavelength of CW lasers from 0.4 to 4 um with automatic operation. OEM-quoted WA-20 specifications list vacuum wavelength readout from 0.4 to 1.0 um, accuracy to plus or minus 1 part in 10^6 , 1.6 s display update, and high/low resolution readout modes. CW laser tuning and drift monitoring where grating spectrometers are slower or less absolute. Fully automatic wavelength measurement without external reference Display update every 1.6 s for tuning and drift checks



MODEL

Burleigh WA-20

CALIBRATION

Available on request

CONDITION

Used

STATUS

In stock

RFQ / SKU

WA-20

LISTING

<https://aumictechlabs.com/products/wa-20-2/>

NIST-traceable cal

SAM registered

30-day returns

NAICS 423690 · 811210 · 541380

This unit

The Burleigh WA-20 Wavemeter is a precision instrument for absolute wavelength measurement of continuous wave lasers across the ultraviolet to mid-infrared spectrum. Built around a scanning Michelson interferometer and an integrated HeNe laser wavelength standard, it delivers traceable measurements without external reference sources. The instrument automatically determines laser

wavelength with high accuracy, making it essential for laser tuning, spectral characterization, and drift monitoring applications. Technical Specifications Wavelength Range: 0.4 μm to 4 μm (vacuum wavelength measured 0.4 μm to 1 μm) Measurement Principle: Scanning Michelson interferometer Internal Calibration: Built-in HeNe laser wavelength standard Accuracy (High Resolution, linewidth < 2 GHz): 0.4–1.0 μm ± 0.001 nm; 1.0–4.0 μm ± 0.004 nm Accuracy (Low Resolution, linewidth < 20 GHz): 0.4–1.0 μm ± 0.01 nm; 1.0–4.0 μm ± 0.01 nm Overall Accuracy: ± 1 part in 10^6 Readout Precision: 0.001 nm (high resolution); 0.01 nm (low resolution) Display Update Rate: Every 1.6 seconds Power: 110 V, 50/60 Hz, 0.5 A Dimensions: 17" W $\times$ 12" D $\times$ 7" H Manufactured in the United States Key Features Automatic wavelength determination eliminates manual calibration overhead Dual accuracy modes accommodate narrow-linewidth (< 2 GHz) and broader-linewidth (< 20 GHz) laser sources Sub-picometer readout resolution in high-resolution mode Real-time display refresh every 1.6 seconds for dynamic measurements D-sub 25-pin connector for data output and system integration Typical Applications Laser wavelength verification and identification Single-frequency laser characterization Wavelength drift analysis and stability monitoring Laser tuning and optimization Spectroscopic and metrological calibration work Compatibility & Integration Data output via D-sub 25-pin connector enables instrument integration into automated test systems and data acquisition setups.

20 Characteristics / Specifications

PARAMETER	VALUE
Model	WA-20
Instrument Type	CW optical wavelength meter
Wavelength Operating Span	0.4 to 4 um
Vacuum Wavelength Measurement Span	0.4 to 1.0 um
Absolute Accuracy Class	plus or minus 1 part in 10 ⁶
Readout Limited Visible	0.001 nm
Readout Limited Infrared Wavenumber	0.01 cm ⁻¹
High Resolution Readout Precision	0.001 nm
Low Resolution Readout Precision	0.01 nm
High Resolution Accuracy 0.4 To 1.0 Um	plus or minus 0.001 nm for linewidth less than 2 GHz
High Resolution Accuracy 1.0 To 4.0 Um	plus or minus 0.004 nm for linewidth less than 2 GHz
Low Resolution Accuracy 0.4 To 1.0 Um	plus or minus 0.01 nm for linewidth less than 20 GHz
Low Resolution Accuracy 1.0 To 4.0 Um	plus or minus 0.01 nm for linewidth less than 20 GHz
Linewidth Condition High Resolution	less than 2 GHz
Linewidth Condition Low Resolution	less than 20 GHz
Display Update Interval	1.6 s
Laser Type Supported	CW
External Reference Required	none for calibration across range
Line Power	110 V 50/60 Hz 0.5 A
Line Frequency	50/60 Hz
Line Current	0.5 A
Dimensions Width	17 inch
Dimensions Depth	12 inch
Dimensions Height	7 inch
Mass	38 lb

PARAMETER	VALUE
Country Of Manufacture	United States
Linewidth	less than 2 GHz

20 Specifications

PARAMETER	VALUE
Applications	CW laser tuning and drift monitoring where grating spectrometers are slower or less absolute.
Display update every 1.6 s for tuning and drift checks	High and low resolution readout modes
Technical Specifications	Model: WA-20

Full OEM specifications

Complete technical content extracted from the manufacturer datasheet. Sparse OEM tables are reconstructed as tables below; other text is preserved as paragraphs.

specifications list vacuum wavelength readout from 0.4 to 1.0 um, accuracy to plus or minus 1 part in 10^6, 1.6 s display update, and high/low resolution readout modes.

Applications

CW laser tuning and drift monitoring where grating spectrometers are slower or less absolute.

Key Features

Fully automatic wavelength measurement without external reference

Display update every 1.6 s for tuning and drift checks

High and low resolution readout modes

Vacuum wavelength measurement 0.4 to 1.0 um

No external calibration source required across operating range

Technical Specifications

Technical Specifications

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Instrument Type	CW optical wavelength meter
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Readout Limited Infrared Wavenumber	0.01 cm^-1
High Resolution Readout Precision	0.001 nm
Low Resolution Readout Precision	0.01 nm
High Resolution Accuracy 0.4 To 1.0 Um	plus or minus 0.001 nm for linewidth less than 2 GHz
High Resolution Accuracy 1.0 To 4.0 Um	plus or minus 0.004 nm for linewidth less than 2 GHz
Low Resolution Accuracy 0.4 To 1.0 Um	plus or minus 0.01 nm for linewidth less than 20 GHz
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Mass	38 lb
Country Of Manufacture	United States

Notes

From Burleigh WA-20 wavelength meter published specification listings quoting OEM accuracy and readout tables. Electrical and mechanical figures from equipment documentation accompanying those listings.

Available from Aumictech

Used and refurbished unit evaluated in-house. Calibration: Available on request. Used · In stock.

Request a quote: sales@aumictech.com · +1 (484) 841-9341

Aumictech

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Technical content from manufacturer specifications. Unit photo/stock from Aumictech listing when available. Specifications subject to OEM documentation and unit condition.